

Notice of References Cited	Application/Control No. 10/524,366		Applicant(s)/Patent Under Reexamination MEYER ET AL.	
	Examiner PATRICIA L. HAILEY		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2006/0009545 A1	01-2006	Frahn et al.	523/200
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